**TTTC: Test Technology Technical Council**

### TTTC IN GENERAL

**PURPOSE:** The Test Technology Technical Council is a volunteer professional organization sponsored by the IEEE Computer Society. The goals of TTTC are to contribute to members' professional development and advancement and to help them solve engineering problems in electronic test, and help advance the state-of-the-art. In particular, TTTC aims at facilitating the knowledge flow in an integrated manner, to ensure overall quality in terms of technical excellence, fairness, openness, and equal opportunities.

**MEMBERSHIP:** Membership is open to all individuals interested in test engineering at a professional level.

**DUES:** There are NO dues for TTTC membership and no parent-organization membership requirements.

**BENEFITS:** The TTTC members benefit from personal association with other test professionals. They may have the opportunity to be involved on a wide range of committees. They receive appropriate and updated information and announcements. There are substantial reductions in fees for TTTC-sponsored meetings and tutorials for members of IEEE and/or IEEE Computer Society.

### TTTC ACTIVITIES

**TECHNICAL MEETINGS:** To spread technical knowledge and advance the state-of-the-art, TTTC sponsors many well-known conferences and symposia and holds numerous regional and topical workshops worldwide.

**STANDARDS:** TTTC initiates, nurtures and encourages new test standards. TTTC-initiated Working Groups have produced numerous IEEE standards, including the 1149 series used throughout the industry.

**TECHNICAL ACTIVITIES:** TTTC sponsors a number of Technical Activity Committees (TACs) that address emerging test technology topics and guide a wide range of activities.

**TUTORIALS and EDUCATION:** TTTC sponsors a comprehensive Test Technology Educational Program (TTEP). This program provides opportunities for design and test professionals to update and expand their knowledge base in test technology, and to earn official accreditation from IEEE TTTC, upon the completion of four full day tutorials proposed by TTEP.

### TTTC CONTACT

**TTTC On-Line:** The TTTC Web Site at http://tab.computer.org/tttcoffers samples of the TTTC Newsletter, information about technical activities, conferences, workshops and standards, and links to the Web pages of a number of TTTC-sponsored technical meetings.

**Becoming a MEMBER:** Becoming a TTTC Member is extremely simple. You may either contact by phone or e-mail the TTTC office, or fill and submit a TTTC application form, or visit the membership section of the TTTC web site.

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Test Resource Partitioning
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Test Synthesis
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| IEEE P7581 | Frans DE JONG Philips Electronic – The Netherlands | frans.de.jong@philips.com |

TTTC Sponsored Technical Meetings in 2004

1/28-1/30 International Workshop on Electronic, Design, Test and Applications, Perth, Australia
2/16-2/22 Design Automation and Test in Europe, Paris, France
2/24-2/27 Pacific Northwest Test Workshop, Bodega Bay, CA, USA
3/8-3/10 Latin American Test Workshop, Cartagena, Colombia
4/4-4/7 International Test Synthesis Workshop, Santa Barbara, CA, USA
4/18-4/21 Design and Diagnosis of Electronic Circuits and Systems Workshop, Stara Lesna, Slovakia
4/25/2004 Current & Defect Based Testing Workshop, Napa Valley, CA, USA
4/25-4/29 VLSI Test Symposium, Napa Valley, CA, USA
4/12-4/30 International Workshop on Test Resource Partitioning, Napa Valley, CA, USA
5/5-5/12 Workshop on Signal Propagation on Interconnects, Heidelberg, Germany
5/12-5/14 Design, Test, Integration and Packaging of MEMS/MOEMS Symposium, Montreux, Switzerland
5/13-5/14 North Atlantic Test Workshop, Essex Junction, VT, USA
5/13-5/15 International Conference on Automation, Quality and Testing, Robotics, Cluj-Napoca, Romania
5/23-5/26 European Test Symposium, Corsica, France
5/26-5/27 International Silicon Debug and Diagnosis Workshop, Ajaccio, Corsica, France
6/16-6/20 Workshop on Test of Wireless Circuits and Systems, Heidelberg, Germany
6/6-6/9 Southwest Test Workshop, San Diego, CA, USA
6/23-6/25 International Mixed Signal Test Workshop, Portland, Oregon, USA
7/12-7/14 International On-Line Testing Symposium, Funchal, Madeira Island, Portugal
8/19-8/30 International Workshop on Memory Technology, Design and Test, San Jose, CA, USA
9/9-9/11 International Workshop on Microprocessor Test and Verification, Austin, TX, USA
9/13-9/14 IC Test Workshop, Univ. of Limerick, Ireland
9/23-9/26 East-West Design & Test Workshop, Yalta, Ukraine
9/29-10/1 International Workshop on Thermal Investigations of ICs and Systems, Cote d'Azur, France
10/14-10/19 International Test Conference, Charlotte, NC, USA
10/28-10/29 GHz/Gbps Test Workshop, Charlotte, NC, USA
10128-10129 Infrastructure Workshop, Charlotte, NC, USA
10129 Electronic Systems Test Workshop, Charlotte, NC, USA
11110-11112 International High Level Design Validation and Test Workshop, San Francisco Bay Area, CA, USA
11115-11117 Asian Test Symposium, Kenting, Taiwan

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